

Application/Control No.	Applicant(s)/Patent under Reexamination
10/529,854	TANAKA, KOJIRO
Examiner	Art Unit
Rin Shen	1657

	SEAR	CHED	
Class	Subclass	Date	Examiner
NA	NA	6/6/2007	BS
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC		
	DATE	EXMR
STN-see printout.	6/6/2007	BS
Priority document checked.	6/6/2007	BS
Inventor name searched.	6/6/2007	BS
SEQ search: NA.	6/6/2007	BS
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